Search Notes



Application/Control No.	Applicant(s)/Patent u Reexamination	nder
10/712,842	YU ET AL.	
Examiner	Art Unit	

Ted M. Wang

SEARCHED				
Class	Subclass	Date	Examiner	
	UPDATED			
375	329, 326	8/4/2008	TW	
375	355, 365	8/4/2008	TW	
375	372	8/4/2008	TW	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	329, 326	8/4/2008	TW	
375	355, 365	8/4/2008	TW	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	8/4/2008	TW	
odp- searched and reviewed from EAST and PALM	8/4/2008	TW	
IEEExplor- advance- (quadrature and (stor* or buffer or regist* or memory) and (filter* and absolute) and correlat*)	8/4/2008	TW	
IEEExplor - author - Yu Y. B, and Zheng Q.	8/4/2008	TW	